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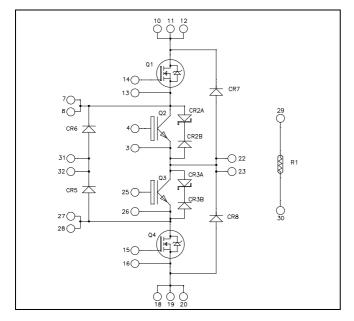




Three level inverter Power Module

Trench & Field Stop IGBT3 Q2, Q3: $V_{CES} = 600V$; $I_C = 30A$ @ $T_C = 80^{\circ}C$

Super junction MOSFET Q1, Q4: $V_{DSS} = 600V$; $I_D = 17A$ @ Tc = 80°C



Application

- Solar converter
- Uninterruptible Power Supplies

Features

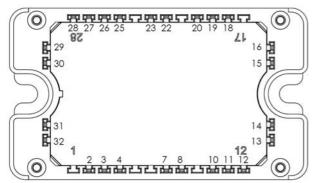
- Q2, Q3 Trench + Field Stop IGBT3
 - Low voltage drop
 - Low tail current
 - Switching frequency up to 20 kHz
 - Low leakage current
 - RBSOA and SCSOA rated

• Q1, Q4 Super junction MOSFET

- Ultra low R_{DSon}
- Low Miller capacitance
- Ultra low gate charge
- Avalanche energy rated
- Very rugged
- Kelvin emitter for easy drive
- Very low stray inductance
- High level of integration
- Internal thermistor for temperature monitoring



- Stable temperature behavior
- Very rugged
- Direct mounting to heatsink (isolated package)
- Low junction to case thermal resistance
- Low profile
- RoHS Compliant



All multiple inputs and outputs must be shorted together Example: 10/11/12; 7/8 ...

All ratings @ $T_i = 25^{\circ}C$ unless otherwise specified

CAUTION: These Devices are sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed.



Q1 & Q4 Absolute maximum ratings (per Super junction MOSFET)

Symbol	Parameter		Max ratings	Unit
V_{DSS}	Drain - Source Voltage		600	V
Ţ	Continuous Drain Current	$T_c = 25$ °C	22	
I_D	Continuous Drain Current	$T_c = 80$ °C	17	A
I_{DM}	Pulsed Drain current	75		
V_{GS}	Gate - Source Voltage		±20	V
R _{DSon}	Drain - Source ON Resistance		99	mΩ
P_D	Power Dissipation	$T_c = 25$ °C	110	W
I_{AR}	Avalanche current (repetitive and non repetitive)		11	A
E _{AR}	Repetitive Avalanche Energy		1.2	mJ
E_{AS}	Single Pulse Avalanche Energy	_	800	IIIJ

Q1 & Q4 Electrical Characteristics (per Super junction MOSFET)

Symbol	Characteristic	Test Conditions	Min	Тур	Max	Unit
I_{DSS}	Zero Gate Voltage Drain Current	$V_{GS} = 0V ; V_{DS} = 600V$			50	μΑ
R _{DS(on)}	Drain – Source on Resistance	$V_{GS} = 10V, I_D = 18A$			99	mΩ
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 1.2 \text{ mA}$	2.5	3	3.5	V
I_{GSS}	Gate – Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA

Q1 & Q4 Dynamic Characteristics (per Super junction MOSFET)

Symbol	Characteristic The Characteristic	Test Conditions	Min	Typ	Max	Unit
C_{iss}	Input Capacitance	$V_{GS} = 0V ; V_{DS} = 100V$		2800		рF
C_{oss}	Output Capacitance	f = 1MHz		130		pr
Q_{g}	Total gate Charge	$V_{GS} = 10V$		14		
Q_{gs}	Gate – Source Charge	$V_{\text{Bus}} = 400 \text{V}$		20		nC
Q_{gd}	Gate – Drain Charge	$I_D = 18A$		60		
$T_{d(on)}$	Turn-on Delay Time	$V_{GS} = 10V$		10		
$T_{\rm r}$	Rise Time	$V_{\text{Bus}} = 400\text{V}$		5		
$T_{d(off)}$	Turn-off Delay Time	$I_D = 18A$		60		ns
T_{f}	Fall Time	$R_G = 3.3\Omega$		5		
R_{thJC}	Junction to Case Thermal Resistance				1.15	°C/W

Q2 & Q3 Absolute maximum ratings (per IGBT)

Symbol	Parameter		Max ratings	Unit
V_{CES}	Collector - Emitter Voltage		600	V
Ţ	Continuous Collector Current	$T_C = 25^{\circ}C$	50	
$I_{\rm C}$	Continuous Conector Current	$T_C = 80$ °C	30	Α
I_{CM}	Pulsed Collector Current	$T_C = 25$ °C	60	
V_{GE}	Gate – Emitter Voltage		±20	V
P_D	Power Dissipation	$T_C = 25^{\circ}C$	90	W
RBSOA	Reverse Bias Safe Operating Area	$T_J = 150$ °C	60A @ 550V	

Q2 & Q3 Electrical Characteristics (per IGBT)

Symbol	Characteristic	Test Conditions	Min	Typ	Max	Unit	
I_{CES}	Zero Gate Voltage Collector Current	$V_{GE} = 0V, V_{CE} =$			250	μΑ	
V _{CE(sat)}	Collector Emitter Saturation Voltage	$V_{GE} = 15V$	$T_j = 25$ °C		1.5	1.9	V
V CE(sat)	Collector Emitter Saturation Voltage	$I_C = 30A$	$T_j = 150$ °C		1.7		·
$V_{GE(th)}$	Gate Threshold Voltage	$V_{GE} = V_{CE}, I_{C} = 400 \mu A$		5.0	5.8	6.5	V
I_{GES}	Gate – Emitter Leakage Current	$V_{GE} = 20V, V_{CE}$	=0V			300	nA

Q2 & Q3 Dynamic Characteristics (per IGBT)

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
Cies	Input Capacitance	$V_{GE} = 0V$			1600		
C_{oes}	Output Capacitance	$V_{CE} = 25V$			110		pF
Cres	Reverse Transfer Capacitance	f = 1MHz			50		
Q_{G}	Gate charge	$V_{GE}=\pm 15V, I_{C}=3V_{CE}=300V$	0A		0.3		μС
$T_{d(on)}$	Turn-on Delay Time	Inductive Switch	ning (25°C)		110		
T_{r}	Rise Time	$V_{GE} = \pm 15V$			45		
$T_{d(off)}$	Turn-off Delay Time	$V_{\text{Bus}} = 300\text{V}$ $I_{\text{C}} = 30\text{A}$			200		ns
T_{f}	Fall Time	$R_G = 10\Omega$			40		
$T_{d(on)}$	Turn-on Delay Time		Inductive Switching (150°C)		120		
$T_{\rm r}$	Rise Time	$V_{GE} = \pm 15V$ $V_{Bus} = 300V$			50		ns
$T_{d(off)}$	Turn-off Delay Time	$I_C = 30A$			250		115
T_{f}	Fall Time	$R_G = 10\Omega$			60		
Eon	Turn-on Switching Energy	$V_{GE} = \pm 15V$	$T_j = 25^{\circ}C$		0.16		mJ
Lon	Turn on Switching Energy	$V_{Bus} = 300V$	$T_j = 150$ °C		0.3		1113
$E_{ m off}$	Turn-off Switching Energy	$I_C = 30A$	$T_j = 25$ °C		0.7		mJ
2011	· · · · · · · · · · ·	$R_G = 10\Omega$	$T_j = 150$ °C		1.05		
I_{sc}	Short Circuit data	$V_{GE} \le 15V ; V_{Bus} = 360V$ $t_p \le 6\mu s ; T_j = 150^{\circ}C$			150		A
R_{thJC}	Junction to Case Thermal Resistance					1.6	°C/W

CR2 & CR3 diode ratings and characteristics (per device)

	Symbol	Characteristic	Test Conditions	Min	Typ	Max	Unit
	$V_{\rm F}$	Diode + tranzorb Forward Voltage	$I_F = 10A$		10		V
ľ	R_{thJC}	Junction to Case Thermal Resistance				8	°C/W



CR5 & CR6 diode ratings and characteristics (per diode)

Symbol	Characteristic	Test Conditions	Test Conditions		Typ	Max	Unit
V_{RRM}	Peak Repetitive Reverse Voltage					600	V
I_{RM}	Reverse Leakage Current	$V_R=600V$				25	μΑ
I_{F}	DC Forward Current		$Tc = 80^{\circ}C$		30		A
		$I_F = 30A$			1.8	2.2	
V_{F}	Diode Forward Voltage	$I_F = 60A$			2.2		V
		$I_F = 30A$	$T_j = 125$ °C		1.5		V
+	Payarga Pagayary Tima		$T_j = 25$ °C		25		10 G
t_{rr}	Reverse Recovery Time	$I_F = 30A$	$T_j = 125$ °C		160		ns
0	Davara Dagayary Chargo	$V_R = 400V$ $di/dt = 200A/\mu s$	$T_j = 25$ °C		35		nC
Qrr	Reverse Recovery Charge	·	$T_j = 125$ °C		480		iiC
E _{rr}	Reverse Recovery Energy	$\begin{split} I_F &= 30A \\ V_R &= 400V \\ di/dt &= 1000A/\mu s \end{split}$	$T_j = 125$ °C		0.6		mJ
R_{thJC}	Junction to Case Thermal Resistance					1.2	°C/W

CR7 & CR8 diode ratings and characteristics (per diode)

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
V_{RRM}	Peak Repetitive Reverse Voltage					1200	V
I_{RM}	Reverse Leakage Current	$V_R = 1200V$				100	μΑ
I_F	DC Forward Current		$Tc = 80^{\circ}C$		30		A
		$I_F = 30A$			2.6	3.1	
V_{F}	Diode Forward Voltage	$I_F = 60A$			3.2		V
	_	$I_F = 30A$	$T_j = 125$ °C		1.8		V
4	Daviana Dagayany Tima		$T_j = 25$ °C		300		***
t_{rr}	Reverse Recovery Time	$I_F = 30A$	$T_j = 125$ °C		380		ns
Q_{rr}	Reverse Recovery Charge	$V_R = 800V$ $di/dt = 200A/\mu s$	$T_j = 25$ °C		360		пC
Qrr	Reverse Recovery Charge	·	$T_j = 125$ °C		1700		пс
E _{rr}	Reverse Recovery Energy	$\begin{split} I_F = 30A \\ V_R = 800V \\ di/dt = &1000A/\mu s \end{split}$	$T_j = 125$ °C		1.6		mJ
R_{thJC}	Junction to Case Thermal Resistance					1.2	°C/W

Temperature sensor NTC (see application note APT0406 on www.microsemi.com for more information).

Symbol	Characteristic		Min	Typ	Max	Unit
R ₂₅	Resistance @ 25°C			50		kΩ
$\Delta R_{25}/R_{25}$				5		%
B _{25/85}	$T_{25} = 298.15 \text{ K}$			3952		K
$\Delta \mathrm{B/B}$		T _C =100°C		4		%

$$R_T = \frac{R_{25}}{\exp \left[B_{25/85} \left(\frac{1}{T_{25}} - \frac{1}{T} \right) \right]} \quad \text{T: Thermistor temperature}$$

$$R_T: \text{Thermistor value at T}$$

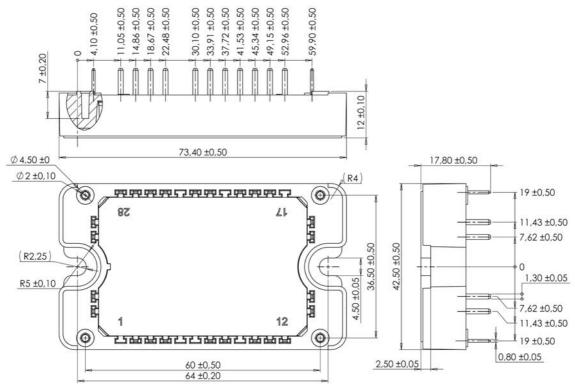


Thermal and package characteristics

Symbol	Characteristic			Min	Max	Unit
V_{ISOL}	RMS Isolation Voltage, any terminal to case t = 1 min, 50/60Hz			4000		V
T_{J}	Operating junction temperature range			-40	175*	
T_{JOP}	Recommended junction temperature under switching conditions			-40	T _J max -25	°C
T_{STG}	Storage Temperature Range			-40	125	
$T_{\rm C}$	Operating Case Temperature			-40	125	
Torque	Mounting torque	To heatsink	M4	2	3	N.m
Wt	Package Weight				110	g

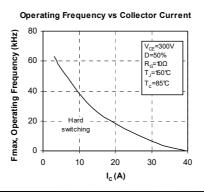
^{*} Tjmax = 150°C for Q1 & Q4

Package outline (dimensions in mm)

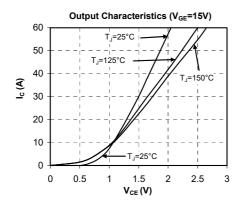


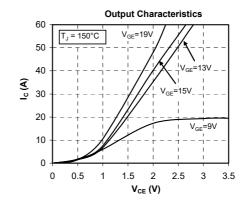
See application note 1906 - Mounting Instructions for SP3F Power Modules on www.microsemi.com

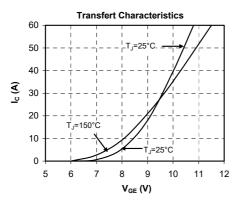
Q2 & Q3 Typical performance curve

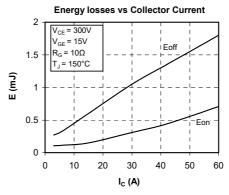


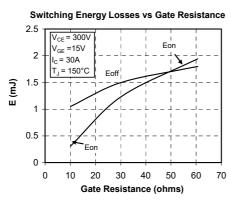


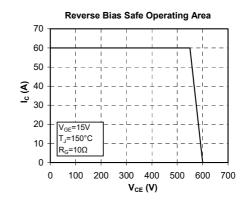


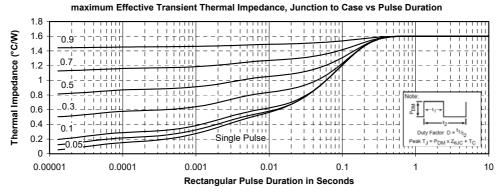






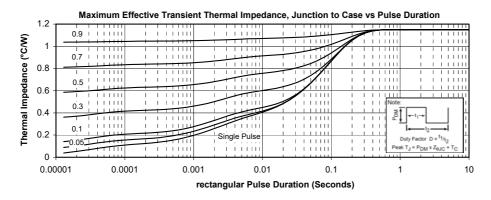


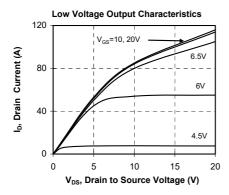


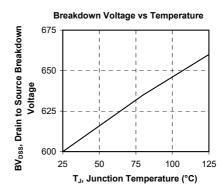


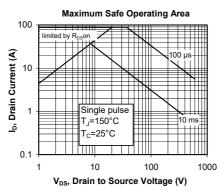


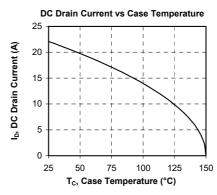
Q1 & Q4 Typical performance curve

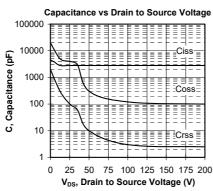


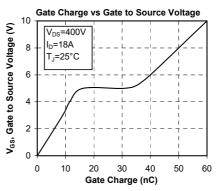






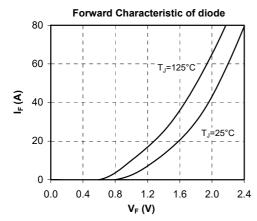


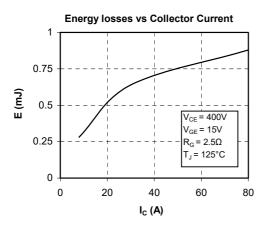


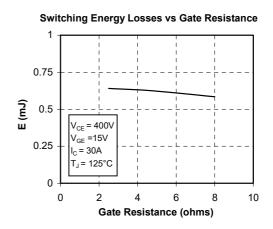


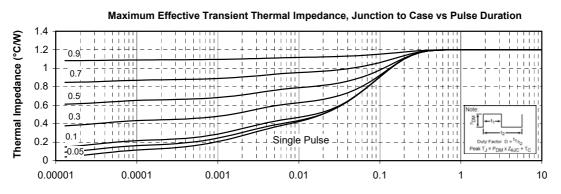


CR5 & CR6 Typical performance curve





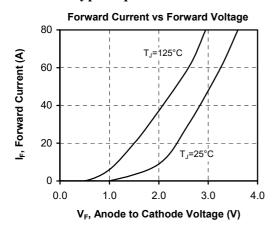




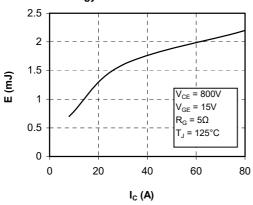
Rectangular Pulse Duration (Seconds)



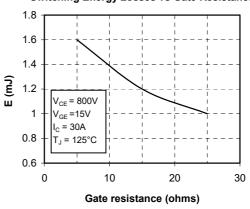
CR7 & CR8 Typical performance curve



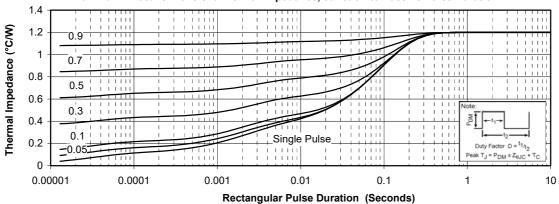
Energy losses vs Collector Current



Switching Energy Losses vs Gate Resistance









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